

Thinning-stable point processes as a model for bursty spatial data

Sergei Zuyev

Chalmers University of Technology, Gothenburg, Sweden

Smögen, Aug. 29th 2014

Challenge: spatial burstiness



Stability

Definition

A random vector ξ (generally, a random element on a **convex cone**) is called **strictly α -stable** (notation: $\text{St}\alpha\text{S}$) if for any $t \in [0, 1]$

$$t^{1/\alpha}\xi' + (1-t)^{1/\alpha}\xi'' \stackrel{\mathcal{D}}{=} \xi, \quad (1)$$

where ξ' and ξ'' are independent copies of ξ .

Stability and CLT

Only $\text{St}\alpha\text{S}$ vectors ξ can appear as a weak limit

$$n^{-1/\alpha}(\zeta_1 + \dots + \zeta_n) \implies \xi.$$

$D_\alpha S$ point processes

Definition

A point process Φ (or its probability distribution) is called **discrete α -stable** or **α -stable with respect to thinning** (notation $D_\alpha S$), if for any $0 \leq t \leq 1$

$$t^{1/\alpha} \circ \Phi' + (1-t)^{1/\alpha} \circ \Phi'' \stackrel{\mathcal{D}}{=} \Phi,$$

where Φ' and Φ'' are independent copies of Φ and $t \circ \Phi$ is **independent thinning** of its points with retention probability t .

Discrete stability and limit theorems

Let Ψ_1, Ψ_2, \dots be a sequence of i. i. d. point processes and $S_n = \sum_{i=1}^n \Psi_i$. If there exists a PP Φ such that for some α we have

$$n^{-1/\alpha} \circ S_n \implies \Phi \quad \text{as } n \rightarrow \infty$$

then Φ is $D_\alpha S$.

CLT

When intensity measure of Ψ is σ -finite, then $\alpha = 1$ and Φ is a Poisson processes. Otherwise, Φ has infinite intensity measure – **bursty**

D_α S point processes and St_α S random measures

Cox process

Let ξ be a random measure on the space X . A point process Φ on X is a **Cox process** directed by ξ , when, conditional on ξ , realisations of Φ are those of a Poisson process with intensity measure ξ .

Characterisation of $D_\alpha S$ PP

Theorem

A PP Φ is a (regular) $D_\alpha S$ iff it is a **Cox process** Π_ξ **with a $St_\alpha S$ intensity measure ξ** , i.e. a random measure satisfying

$$t^{1/\alpha} \xi' + (1-t)^{1/\alpha} \xi'' \stackrel{\mathcal{D}}{=} \xi.$$

Its p.g.fl. is given by

$$G_\Phi[u] = \mathbf{E} \prod_{x_i \in \Phi} u(x_i) = \exp \left\{ - \int_{\mathbb{M}_1} \langle 1-u, \mu \rangle^\alpha \sigma(d\mu) \right\}, \quad 1-u \in \text{BM}$$

for some locally finite spectral measure σ on the set \mathbb{M}_1 of probability measures.

$D_\alpha S$ PPs exist only for $0 < \alpha \leq 1$ and for $\alpha = 1$ these are Poisson.

Sibuya point processes

Definition

A r.v. γ has **Sibuya distribution**, $\text{Sib}(\alpha)$, if

$$g_\gamma(s) = 1 - (1 - s)^\alpha, \quad \alpha \in (0, 1).$$

It corresponds to the number of trials to get the first success in a series of Bernoulli trials with probability of success in the k th trial being α/k .

Sibuya point processes

Definition

A r.v. γ has **Sibuya distribution**, $\text{Sib}(\alpha)$, if

$$g_\gamma(s) = 1 - (1 - s)^\alpha, \quad \alpha \in (0, 1).$$

It corresponds to the number of trials to get the first success in a series of Bernoulli trials with probability of success in the k th trial being α/k .

Sibuya point processes

Let μ be a probability measure on X . The point process Υ on X is called the **Sibuya point process** with **exponent α** and **parameter measure μ** if $\Upsilon(X) \sim \text{Sib}(\alpha)$ and each point is μ -distributed independently of the other points. Its distribution is denoted by $\text{Sib}(\alpha, \mu)$.

Examples of Sibuya point processes

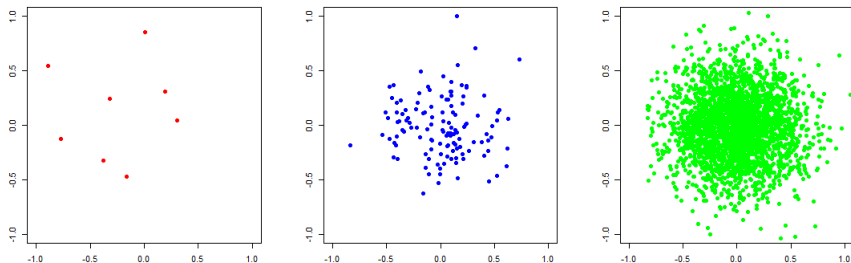


Figure : Sibuya processes: $\alpha = 0.4$, $\mu \sim \mathcal{N}(0, 0.3^2\mathbf{I})$

$D_\alpha S$ point processes as cluster processes

Theorem Davydov, Molchanov & Z'11

Let \mathbb{M}_1 be the set of all probability measures on X . A **regular** $D_\alpha S$ point process Φ can be represented as a **cluster process** with

- **Poisson centre process** on \mathbb{M}_1 driven by intensity measure σ ;
- **Component processes** being Sibuya processes $\text{Sib}(\alpha, \mu)$, $\mu \in \mathbb{M}_1$.

Statistical Inference for $D_\alpha S$ processes

We assume the observed realisation comes from a **stationary and ergodic $D_\alpha S$ process** without multiple points.

Statistical Inference for $D_\alpha S$ processes

We assume the observed realisation comes from a **stationary and ergodic $D_\alpha S$ process** without multiple points.

Such processes are characterised by:

- λ – the Poisson parameter: mean number of clusters per unit volume
- α – the stability parameter

Statistical Inference for $D_\alpha S$ processes

We assume the observed realisation comes from a **stationary and ergodic $D_\alpha S$ process** without multiple points.

Such processes are characterised by:

- λ – the Poisson parameter: mean number of clusters per unit volume
- α – the stability parameter
- A probability distribution $\sigma_0(d\mu)$ on \mathbb{M}_1 (the distribution of the Sibuya parameter measure)

Construction

- 1 Generate a homogeneous Poisson PP $\sum_i \delta_{y_i}$ of centres of intensity λ ;
- 2 For each y_i generate independently a probability measure μ_i from distribution σ_0 ;
- 3 Take the union of independent Sibuya clusters $\text{Sib}(\alpha, \mu_i(\cdot - y_i))$.

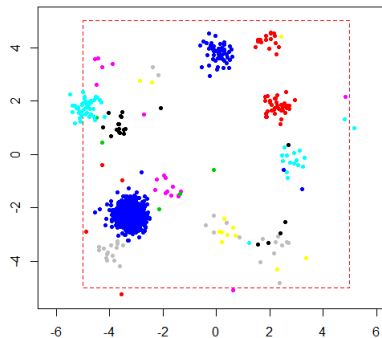
Example of $D_\alpha S$ point process

Figure : $\lambda = 0.4$, $\alpha = 0.6$, $\sigma_0 = \delta_\mu$, where $\mu \sim \mathcal{N}(0, 0.3^2 I)$

Parameters to estimate

Consider the case when all the clusters have the same distribution, so that $\sigma_0 = \delta_\mu$ for some $\mu \in \mathbb{M}_1$.

We always need to estimate λ and α , often also μ .

Parameters to estimate

Consider the case when all the clusters have the same distribution, so that $\sigma_0 = \delta_\mu$ for some $\mu \in \mathbb{M}_1$.

We always need to estimate λ and α , often also μ .

We consider three possible cases for μ :

- μ is already **known**
- μ is unknown but lies in a **parametric class** (e.g. $\mu \sim \mathcal{N}(0, \sigma^2 \mathbf{I})$ or $\mu \sim U(B_r(0))$)
- μ is totally **unknown**

Estimation of μ

Idea

Identifying a big cluster in the dataset and using it to estimate μ .

Estimation of μ

Idea

Identifying a big cluster in the dataset and using it to estimate μ .

How to distinguish clusters in the configuration? How to identify at least the biggest clusters?

Estimation of μ

Idea

Identifying a big cluster in the dataset and using it to estimate μ .

How to distinguish clusters in the configuration? How to identify at least the biggest clusters?

- Interpreting data as a mixture model

Estimation of μ

Idea

Identifying a big cluster in the dataset and using it to estimate μ .

How to distinguish clusters in the configuration? How to identify at least the biggest clusters?

- Interpreting data as a mixture model
- Expectation-Maximisation algorithm

Estimation of μ

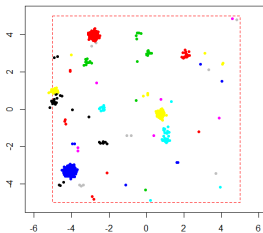
Idea

Identifying a big cluster in the dataset and using it to estimate μ .

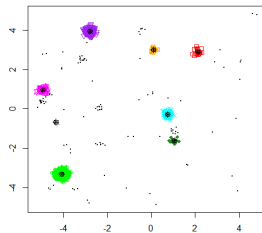
How to distinguish clusters in the configuration? How to identify at least the biggest clusters?

- Interpreting data as a mixture model
- Expectation-Maximisation algorithm
- Bayesian Information Criterion

Example: gaussian spherical clusters, 2D case



(a) Original process



(b) Clustered process

Figure : $D_{\alpha}S$ process with Gaussian clusters: $\lambda = 0.5$, $\alpha = 0.6$, covariance matrix $0.1^2 I$. `mclust` R-procedure with Poisson noise.

Estimation of μ

After we single out one big cluster:

- we estimate μ using kernel density or we just use the sample measure

Estimation of μ

After we single out one big cluster:

- we estimate μ using kernel density or we just use the sample measure
- if μ is in a parametric class we estimate the parameters

Overlapping clusters - heavy thinning approach

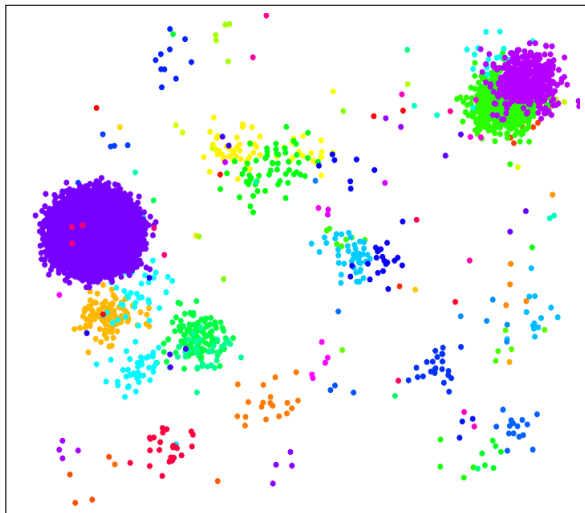


Figure : $\lambda = 0.4$, $\alpha = 0.6$, $\mu_x \sim \mathcal{N}(x, 0.5^2\mathbf{I})$

Estimation of λ and α

When μ is known or have already been estimated, we suggest these

Estimation methods for λ and α

- 1 via void probabilities

Estimation of λ and α

When μ is known or have already been estimated, we suggest these

Estimation methods for λ and α

- 1 via void probabilities
- 2 via the p.g.f. of the counts distribution

Void probabilities for $D_\alpha S$ point processes

The void probabilities (which characterise the distribution of a simple point process) are given by

$$\mathbf{P}\{\Phi(B) = 0\} = \exp \left\{ -\lambda \int_A \mu(B)^\alpha dx \right\}.$$

Estimation of void probabilities

Unbiased estimator for the void probability function

Let $\{x_i\}_{i=1}^n \subseteq A$ a sequence of *test points* and $r_i = \text{dist}(x_i, \text{supp } \Phi)$, then

$$\hat{G}(r) = \frac{1}{n} \sum_{i=1}^n \mathbf{I}_{\{r_i > r\}}$$

is an unbiased estimator for $\mathbf{P}\{\Phi(B_r(0)) = 0\}$.

Then α and λ are estimated by the best fit to this curve.

Example: uniformly distributed clusters, 1D case

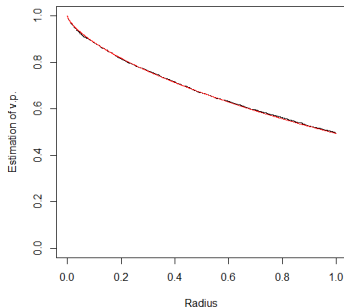


Figure : $\lambda = 0.3$, $\alpha = 0.7$, $\mu \sim U(B_1(0))$, $|A| = 3000$

Estimated values: $\hat{\lambda} = 0.29$, $\hat{\alpha} = 0.68$. Requires big

data!

Void probabilities for thinned processes

p.g.fl. of $D_\alpha S$ processes

$$G_\Phi[h] = \exp \left\{ - \int_{\mathbb{S}} \langle 1 - h, \mu \rangle^\alpha \sigma(d\mu) \right\}, \quad 1 - h \in \mathbf{BM}(X).$$

p.g.fl. of a p -thinned point process

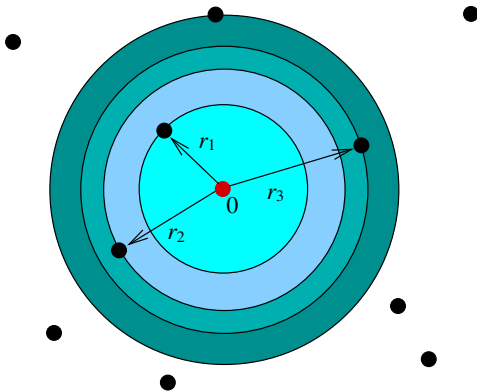
$$G_{p \circ \Phi}[h] = \exp \left\{ - p^\alpha \int_{\mathbb{S}} \langle 1 - h, \mu \rangle^\alpha \sigma(d\mu) \right\}, \quad p \in [0, 1], \quad 1 - h \in \mathbf{BM}(X).$$

$$\sigma(\{\mu(\cdot - x), x \in B\}) = \lambda \cdot |B| \implies \alpha_{new} = \alpha, \lambda_{new} = \lambda \cdot p^\alpha.$$

Estimation via thinned process

There is no need to simulate p -thinning!

Let r_k be the distance from 0 to the k -th closest point in the configuration.



Estimation via thinned process

$$\begin{aligned} & \mathbf{P}\{(p \circ \Phi)(B_r(0)) = 0\} \\ &= \sum_{k=1}^{\Phi} \mathbf{P}\{\text{"the closest survived point is the } k\text{-th"}\} \mathbf{P}\{r_k > r\} \\ &= \sum_{k=1}^{\Phi} p(1-p)^{k-1} \mathbf{P}\{r_k > r\} \end{aligned}$$

Estimation via thinned process

$$\begin{aligned}
 & \mathbf{P}\{(p \circ \Phi)(B_r(0)) = 0\} \\
 &= \sum_{k=1}^{\Phi} \mathbf{P}\{\text{"the closest survived point is the } k\text{-th"}\} \mathbf{P}\{r_k > r\} \\
 &= \sum_{k=1}^{\Phi} p(1-p)^{k-1} \mathbf{P}\{r_k > r\}
 \end{aligned}$$

Unbiased estimator for the void probability function

Let $\{x_i\}_{i=1}^n \subseteq A$ a sequence of *test points* and $r_{i,k}$ be the distance from x_i to its k -closest point of $\text{supp } \Phi$. Then

$$\widehat{G}(r) = \frac{1}{n} \sum_{i=1}^n \sum_{k=0}^{\infty} p(1-p)^{k-1} \mathbf{1}_{\{r_{i,k} > r\}}$$

Example: uniform clusters, 1D case

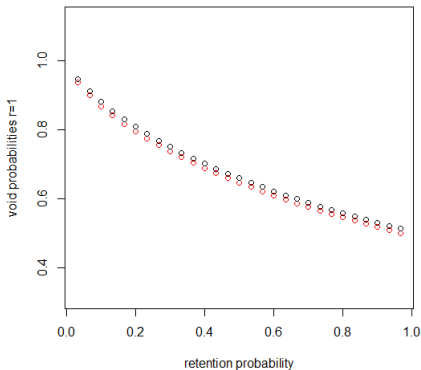


Figure : Estimation of v.p. of the thinned process for a process generated with $\lambda = 0.3$, $\alpha = 0.7$, $\mu \sim U(B_1(0))$, $|A| = 1000$

Estimated values: $\hat{\lambda} = 0.29$, $\hat{\alpha} = 0.72$

Counts distribution

Putting $u(x) = 1 - (1 - s) \mathbf{1}_B(x)$ with $s \in [0, 1]$, in the p.g.fl. expression, we get the p.g.fl. of the counts $\Phi(B)$ for any set B :

$$\psi_{\Phi(B)}(s) := \mathbb{E}[s^{\Phi(B)}] = \exp \left\{ - (1 - s)^\alpha \int_S \mu(B)^\alpha \sigma(d\mu) \right\}. \quad (2)$$

It is a heavy-tailed distribution with $\mathbf{P}\{\Phi(B) > x\} = L(x) x^{-\alpha}$, where L is slowly-varying.

Estimation via counts distribution

The empirical p.g.f. is then

$$\widehat{\psi}_{\Phi(B)}^n(s) := \frac{1}{n} \sum_{i=1}^n s^{\Phi(B_i)} \quad \forall s \in [0, 1],$$

where B_i , $i = 1, \dots, n$, are translates of a fixed reference set B and it is an unbiased estimator of $\psi_{\Phi(B)}$. It is then fitted to (2) for a range of s estimating λ and α .

We also tried the **Hill plot** from extremal distributions inference to estimate α , but the results were poor!

Conclusions

Simulation studies looked at the bias and variance in the estimation of α , λ in different situations:

- Big sample – moderate sample
- Overlapping clusters (large λ) – separate clusters (small λ)
- Heavy clusters (small α) – moderate clusters (α close to 1)

Best methods

- The simplest void probabilities method is preferred for large datasets or for moderate datasets with separated clusters. It best estimates α , but in the latter case λ is best estimated by counts p.g.f. fitting.

Best methods

- The simplest void probabilities method is preferred for large datasets or for moderate datasets with separated clusters. It best estimates α , but in the latter case λ is best estimated by counts p.g.f. fitting.
- λ is best estimated by void probabilities with thinning method which produces best estimates in all the situations apart from moderate separated clusters. But it is also more computationally expensive.

Best methods

- The simplest void probabilities method is preferred for large datasets or for moderate datasets with separated clusters. It best estimates α , but in the latter case λ is best estimated by counts p.g.f. fitting.
- λ is best estimated by void probabilities with thinning method which produces best estimates in all the situations apart from moderate separated clusters. But it is also more computationally expensive.
- As common in modern Statistics, all methods should be tried and consistency in estimated values gives more trust to the model.

Fête de la Musique data



Figure : Estimated $\hat{\alpha} = 0.17 - 0.28$ depending on the way base stations records are extrapolated to spatial positions of callers

Generalisations

For the Paris data we observed a bad fit of cluster size to Sibuya distribution. Possible cure:

F-stable point processes when thinning is replaced by more general subcritical **branching operation**. Multiple points are now also allowed.

References

- 1 Yu. Davydov, I. Molchanov and SZ **Stability for random measures, point processes and discrete semigroups**, *Bernoulli*, **17**(3), 1015-1043, 2011
- 2 espi, B. Spinelli and SZ **Inference for discrete stable point processes** (under preparation)
- 3 G. Zanella and SZ **F-stable point processes** (under preparation)

Thank you!



Questions?